## Notice of References Cited Application/Control No. 10/020,304 Examiner A. Sefer Applicant(s)/Patent Under Reexamination RAVINDRA ET AL Art Unit 2826 Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,767,557	06-1998	Kizilyalli	257/403
	В	US-6,066,880	05-2000	Kusunoki	257/379
	С	US-6,222,234	04-2001	Imai	257/347
	D	US-5,998,828	12-1999	Oeno et al	257/315
	Ε	US-4,302,764	11-1981	Fang et al	357/23
	F	US-6,462,379	10-2002	Higashi et al	257/347
	G	US-6,373,102	04-2002	Huang	257/345
	Н	US-5,208,473	05-1993	Komori et al	257/345
	ı	US-6,221,703	04-2001	Liu et al	437/174
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 9-321276	12-1997	Japan	Tashiro et al	
	0	JP 2-280381	11-1990	Japan	Takahasi et al	
	Р					
	Q			•		
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	v	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.